

AdAM: Adaptive Approximate Multiplier for Fault Tolerance in DNN Accelerators

Taheri, Mahdi; Cherezova, Natalia; Nazari, Samira; Azarpeyvand, Ali; Ghasempouri, Tara; Daneshtalab, Masoud; Raik, Jaan; Jenihhin, Maksim IEEE transactions on device and materials reliability 2024 / p. 66-75 : ill <https://doi.org/10.1109/TDMR.2024.3523386>

AdAM: adaptive fault-tolerant approximate multiplier for edge DNN accelerators

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Special session : approximation and fault resiliency of DNN accelerators

Ahmadilivani, Mohammad Hasan; Barbareschi, Mario; Barone, Salvatore; Bosio, Alberto; **Daneshtalab, Masoud**; Torca, Salvatore Della; Gavarini, Gabriele; **Jenihhin, Maksim**; **Raik, Jaan**; **Taheri, Mahdi** 2023 IEEE 41st VLSI Test Symposium (VTS) : proceedings 2023 / 10 p. : ill <https://doi.org/10.1109/VTS56346.2023.10140043> [Conference proceeding at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Special session: reliability assessment recipes for DNN accelerators

Ahmadilivani, Mohammad Hasan; Bosio, Alberto; Deveautour, Bastien; Dos Santos, Fernando Fernandes; Guerrero-Balaguera, Juan-David; **Jenihhin, Maksim**; Kritikakou, Angeliki; Sierra, Robert Limas; **Raik, Jaan**; **Taheri, Mahdi** 42nd IEEE VLSI Test Symposium, VTS 2024 2024 / 11 p. : ill <https://doi.org/10.1109/VTS60656.2024.10538707> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

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